

1 Study the particle identification performance for  
2  $K_s^0 \longrightarrow \pi^+ \pi^-$  decays using sPlot method

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7 **Abstract**

8 The  $K_s^0 \longrightarrow \pi^+ \pi^-$  sample gives access to low momentum pions, which are  
9 useful for studying the particle identification performance. In this work, we have  
10 validated the sPlot technique using Belle II simulated sample for  $K_s^0 \longrightarrow \pi^+ \pi^-$   
11 at integrated luminosity of  $10\text{fb}^{-1}$ . The Belle II is the upgraded experimen-  
12 tal facility at SuperKEKB, KEK, Japan. In this work, we study the relative  
13 difference between true efficiencies and that obtained from the sPlot technique  
14 for different pion-identification criteria in bins of momentum and cosine of the  
15 polar angle. This study is now included as part of the Belle II Systematic  
16 Correction Framework.

# 1 Introduction

An inclusive sample of  $K_s^0 \rightarrow \pi^+\pi^-$  decays provides access to a large sample of charged pions with momentum below 1 GeV/c. Such pions can be used to study the performance of the particle-identification (PID) algorithms at low momentum. The aim of this work is to develop an analysis method based on the sPlot technique [1], in simulation and to study the PID performance in the context of the Belle II Systematic Correction Framework [2]. The Belle II [3] is an experimental facility at SuperKEKB [4], located in Tsukuba, Japan.

## 2 Reconstruction of $K_s^0 \rightarrow \pi^+\pi^-$

Using  $10 \text{ fb}^{-1}$  of centrally produced Monte Carlo events, pairs of oppositely charged pion tracks are combined to reconstruct the mass of  $K_s^0$ , denoted by  $m(\pi^+\pi^-)$ . The  $K_s^0$  decay time is required to exceed 0.007 ns, to suppress the combinatorial background. The transverse distance of the  $K_s^0$  decay vertex from the origin is required to be less than 3.5 cm, corresponding to the distance of the first layer of the Belle II Silicon Vertex Detector(SVD) [3].

## 3 Results

The  $m(\pi^+\pi^-)$  peak is modelled using the sum of a Gaussian and a Johnson's  $S_U$  [5] function and the background is modelled using a 1<sup>st</sup> order Chebychev polynomial. A binned least squares fit is performed over the entire momentum range as shown in Figure 1 (left). The sWeights thus computed from this fit are used to compute *mc systematic error*, defined as:  $mc\_syst\_error = (\epsilon_{sw} - \epsilon_{tm})/\epsilon_{tm}$ , where  $\epsilon_{sw}$  is the sWeighted efficiency (from splot technique) and  $\epsilon_{tm}$  is the efficiency from truth matching. It is observed that *mc\_syst\_error* increases in the momentum range [0.5, 3.5] GeV/c with the maximum difference being about 7.5% as shown in Figure 1 (right). This dependence of *mc\_syst\_error* in pion momenta may be due to the presence of correlations between  $m(\pi^+\pi^-)$  and momentum of the pions. The impact of these correlations are evaluated by computing sWeights based on independent fits to  $m(\pi^+\pi^-)$  in disjoint bins of momenta: [0.5, 1.5] GeV/c and [1.5, 3.5] GeV/c as shown in Figure 2. No dependence of *mc\_syst\_error* on pion momenta is observed, which implies that pion identification efficiencies obtained from sWeights are in agreement with that obtained from truth matching.

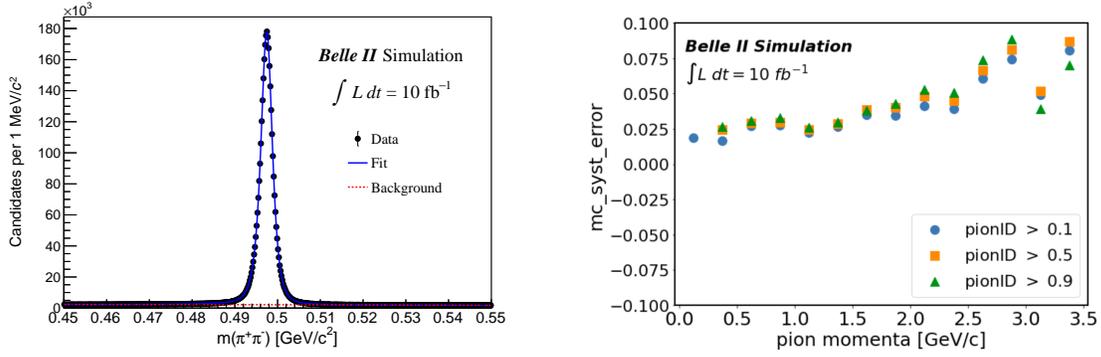


Figure 1: Distribution of  $m(\pi^+\pi^-)$  (left), with fit projections overlaid distributions of  $mc\_syst\_error$  in bins of pion momenta (right).

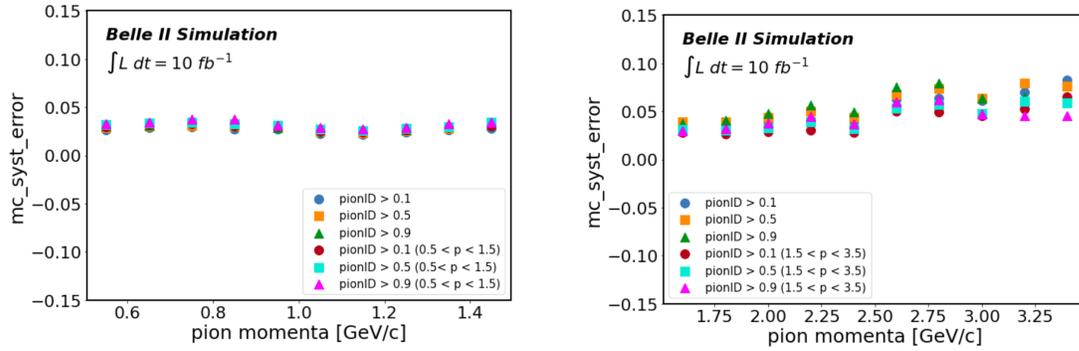


Figure 2:  $mc\_syst\_error$  in bins of pion momenta:  $[0.5, 1.5]$  GeV/c (left) and  $[1.5, 3.5]$  GeV/c (right).

## 48 4 Summary

49 The sPlot technique has been validated using an inclusive sample for  $K_s^0 \rightarrow \pi^+\pi^-$ .  
 50 The truth-matching procedure and the sPlot technique are consistent.

## 51 References

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